

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/600,770	WU, SHENSHE	N
Examiner	Art Unit	
David Buttner	1712	

	SEAR	CHED	
Class	Subclass	Date	Examiner
528	49 ,	12/20/2004	DB
528	54	12/20/2004	DB
528	55	12/20/2004	DB
528	58	12/20/2004	DB
528	61	12/20/2004	DB
528	65	12/20/2004	DB
528	66	12/20/2004	DB
528	76	12/20/2004	DB
528	80	12/20/2004	DB
528	83	12/20/2004	DB
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
	1		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
west	12/20/2004	DB
east	12/20/2004	DB
chem ab	12/20/2004	DB
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